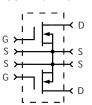
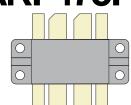


Common Source Push-Pull Pair



ARF475FL



RF POWER MOSFET

N-CHANNEL ENHANCEMENT MODE

165V 300W 150MHz

The ARF475FL is a matched pair of RF power transistors in a common source configuration. It is designed for high voltage push-pull or parallel operation in narrow band ISM and MRI power amplifiers up to 150 MHz.

- Specified 150 Volt, 128 MHz Characteristics:
 - Output Power = 900 Watts Peak

Gain = 15dB (Class AB)

Efficiency = 50% min

- High Performance Push-Pull RF Package.
- High Voltage Breakdown and Large SOA for Superior Ruggedness.
- Low Thermal Resistance.

MAXIMUM RATINGS

All Ratings: $T_C = 25$ °C unless otherwise specified.

Symbol	Parameter	ARF475FL	UNIT	
V _{DSS}	Drain-Source Voltage	500	Volto	
V _{DGO}	Drain-Gate Voltage	500	Volts	
I _D	Continuous Drain Current @ T _C = 25°C (each device)	10	Amps	
V _{GS}	Gate-Source Voltage	±30	Volts	
P _D	Total Device Dissipation @ T _C = 25°C	483	Watts	
T _J ,T _{STG}	G Operating and Storage Junction Temperature Range -55 to 175		00	
T _L	Lead Temperature: 0.063" from Case for 10 Sec.	300	⁺ °C	

STATIC ELECTRICAL CHARACTERISTICS (each device)

Symbol	Characteristic / Test Conditions	MIN	TYP	MAX	UNIT	
BV _{DSS}	Drain-Source Breakdown Voltage (V _{GS} = 0V, I _D = 250 μA)	500			\/alta	
V _{DS(ON)}	On State Drain Voltage (1) (I _{D(ON)} = 5A, V _{GS} = 10V)		2.9	4	Volts	
	Zero Gate Voltage Drain Current (V _{DS} = V _{DSS} , V _{GS} = 0V)			25		
DSS	Zero Gate Voltage Drain Current (V _{DS} = 50V, V _{GS} = 0, T _C = 125°C)			250	μA	
I _{GSS}	Gate-Source Leakage Current (V _{GS} = ±30V, V _{DS} = 0V)			±100	nA	
g _{fs}	Forward Transconductance $(V_{DS} = 15V, I_{D} = 5A)$	3	3.6		mhos	
g _{fs1/} g _{fs2}	Forward Transconductance Match Ratio (V _{DS} = 15V, I _D = 5A)	0.9		1.1		
V _{GS(TH)}	Gate Threshold Voltage (V _{DS} = V _{GS} , I _D = 200mA)	2	3.3	4	Valta	
$\Delta V_{GS(TH)}$	Gate Threshold Voltage Match (V _{DS} = V _{GS} , I _D = 200mA)			0.2	Volts	

THERMAL CHARACTERISTICS

Symbol	Characteristic	MIN	TYP	MAX	UNIT
$R_{\theta JC}$	Junction to Case			0.31	°C /\\/
$R_{\theta CS}$	Case to Sink (Use High Efficiency Thermal Joint Compound and Planar Heat Sink Surface.)		0.1		°C/W

CAUTION: These Devices are Sensitive to Electrostatic Discharge. Proper Handling Procedures Should Be Followed.

Symbol	Characteristic	Test Conditions	MIN	TYP	MAX	UNIT
C _{iss}	Input Capacitance	V _{GS} = 0V		780	900	
C _{oss}	Output Capacitance	V _{DS} = 50V		125	150	pF
C _{rss}	Reverse Transfer Capacitance	f = 1MHz		7	10	
t _{d(on)}	Turn-on Delay Time	V _{GS} = 15V		5.1	10	
t _r	Rise Time	V _{DD} = 250V		4.1	8	ns
t _{d(off)}	Turn-off Delay Time	I _D = I _{D[Cont.]} @ 25°C		12	18	113
t _f	Fall Time	$R_G = 1.6 \Omega$		4.0	7	

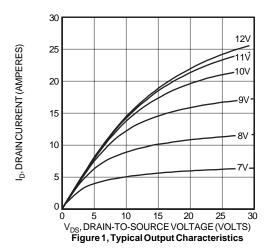
FUNCTIONAL CHARACTERISTICS (Push-Pull Configuration)

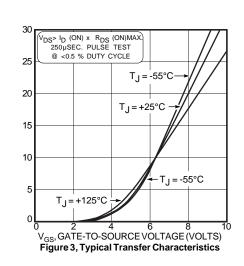
Symbol	Characteristic	Test Conditions	MIN	TYP	МАХ	UNIT
G _{PS}	Common Source Amplifier Power Gain	f = 128 MHz Idq = 15mA $V_{DD} = 150V$	14	16		dB
η	Drain Efficiency	P _{out} = 900W	50	55		%
Ψ	Electrical Ruggedness VSWR 5:1	PW = 3ms 10% duty cycle	No Degradation in Output Power			

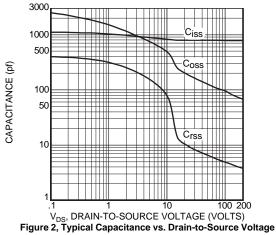
 $[\]bigcirc$ Pulse Test: Pulse width < 380 µS, Duty Cycle < 2%.

APT Reserves the right to change, without notice, the specifications and information contained herein.

Per transistor section unless otherwise specified.







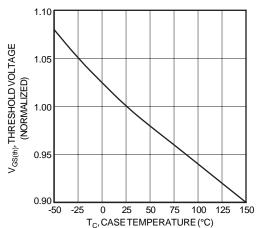
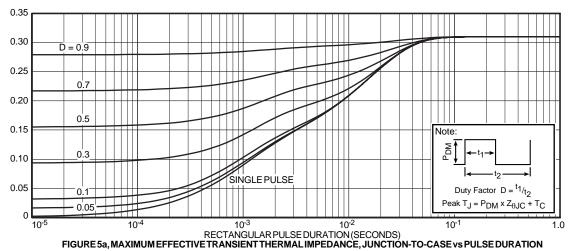


Figure 4, Typical Threshold Voltage vs Temperature

ID, DRAIN CURRENT (AMPERES)



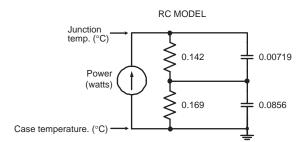
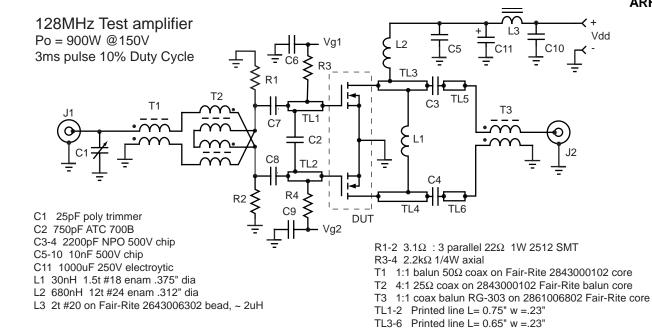


Figure 5b, TRANSIENT THERMAL IMPEDANCE MODEL

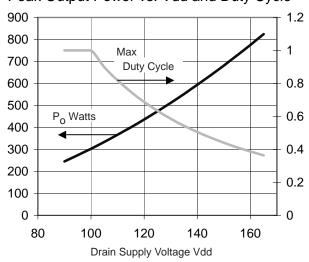
Table 1 - Typical Series Equivalent Large Signal Input - Output Impedance

Freq. (MHz)	Z_{in} (Ω) gate to gate	$Z_{OL}\left(\Omega ight)$ drain - drain
30	5.2 -j10	41 -j20
60	1.37 -j5.2	26 -j25
90	.53 -j2.6	16 -j23
120	.25 -j1.0	10 -j20
150	.25 +j0.2	6.7 -j17

 Z_{in} - Gate -gate shunted with 25 Ω I_{DQ} = 15mA each side Z_{OL} - Conjugate of optimum load for 600 Watts peak output at V_{dd} = 150V 25% duty cycle and PW = 5ms



Peak Output Power vs. Vdd and Duty Cycle



Thermal Considerations and Package Mounting:

The rated power dissipation is only available when the package mounting surface is at 25°C and the junction temperature is 175°C. The thermal resistance between junctions and case mounting surface is 0.3°C/W. When installed, an additional thermal impedance of 0.1°C/W between the package base and the mounting surface is typical. Insure that the mounting surface is smooth and flat. Thermal joint compound must be used to reduce the effects of small surface irregularities. Use the minimum amount necessary to coat the surface. The heatsink should incorporate a copper heat spreader to obtain best results.

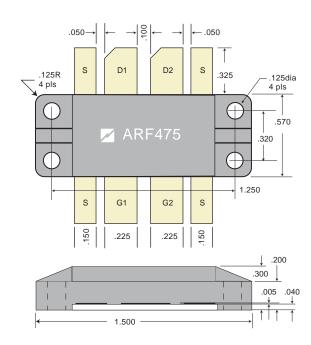
The package design clamps the ceramic base to the heatsink. A clamped joint maintains the required mounting pressure while allowing for thermal expansion of both the base and the heat sink. Four 4-40 (M3) screws provide the required mounting force. T = 6in-lb (0.68N-m).

Notes:

The value of L1 must be adjusted as the supply voltage is changed to maintain resonance in the output circuit. At 128MHz its value changes from approximately 40nH at 100V to 30nH at 150V.

0.23" wide stripline on FR-4 board is ~ 30Ω Z₀

With the 50Ω drain-to-drain load, the duty cycle above 100V must be reduced to insure power dissipation is within the limits of the device. Maximum pulse length should be 100mS or less. See transient thermal impedance, figure 5.



HAZARDOUS MATERIAL WARNING

The white ceramic portion of the device between leads and mounting surface is beryllium oxide, BeO. Beryllium oxide dust is toxic when inhaled. Care must be taken during